

Freeform Search

US Pre-Grant Publication Full-Text Database **US Patents Full-Text Database** US OCR Full-Text Database Database: EPO Abstracts Database JPO Abstracts Database **Derwent World Patents Index** IBM Technical Disclosure Bulletins (near-field microscope) or (near-field probe) Term: Starting with Number 1 10 Documents in Display Format: |-Generate: O Hit List O Hit Count O Side by Side O Image Search Clear Interrupt Search History DATE: Wednesday, March 16, 2005 Printable Copy Create Case **Hit Count Set Name Set Name Query** result set side by side DB=PGPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=YES; OP=ADJ (near-field microscope) or (near-field probe) 355 L3 DB=PGPB, USPT, USOC, EPAB, JPAB; PLUR=YES; OP=ADJ L2 L1 and "near field" 389 L2 (250/216,234,306,307,225,559.09;73/105;359/321,738)![CCLS] 8752 <u>L1</u> L1

END OF SEARCH HISTORY